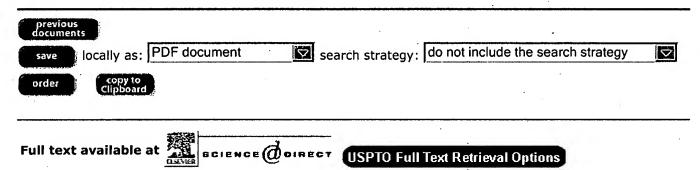


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Title

A new structural framework for parity equation-based failure detection and isolation.

Source

Automatica, {Automatica-UK}, March 1990, vol. 26, no. 2, p. 381-8, 22 refs, CODEN: ATCAA9, ISSN: 0005-1098, UK.

Author(s)

Gerlet-J, Singer-D.

Author affiliation

Gerlet, J., Dept. of Electr. & Comput. Eng., George Mason Univ., Fairfax, VA, USA.

Abstract

Describes a new framework for developing parity equations that prevent incorrect isolation decision under marginal size failures in a decision **process** that tests each residual independently. Test **thresholds** that take the noise conditions into account are set high to reduce the occurrence of false **alarms** while maintaining the algorithm's ability to detect and isolate larger failures. The method is applicable to additive failures on the measured input and output variables and to additive plant disturbances. A transformation algorithm provides a multiple of models that satisfy the isolability requirements. A search procedure utilizing this model redundancy integrates model robustness consideration into the design.

Descriptors

DECISION-THEORY; F REDUNDANCY; RELIABILITY-THEORY; E SEARCH-PROBLEMS.

Classification codes

C1210B Reliability-theory*;

C1140E Game-theory;

E1020 Maintenance-and-reliability*.

Keywords

reliability-theory; failure-isolation; parity-equation-based-failure-detection; **decision-process**; noise-conditions; additive-plant-disturbances; search-procedure; model-redundancy; model-robustness.

Treatment codes

T Theoretical-or-mathematical.

Language

English.

Publication type

Journal-paper.

Availability

CCCC: 0005-1098/90/\$3.00+0.00.

Publication year

1990.

Publication date

19900300.

Edition

1990015.

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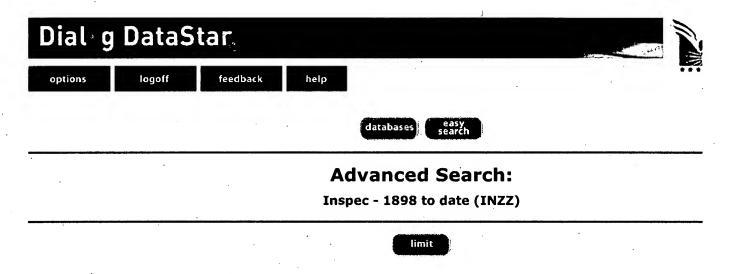
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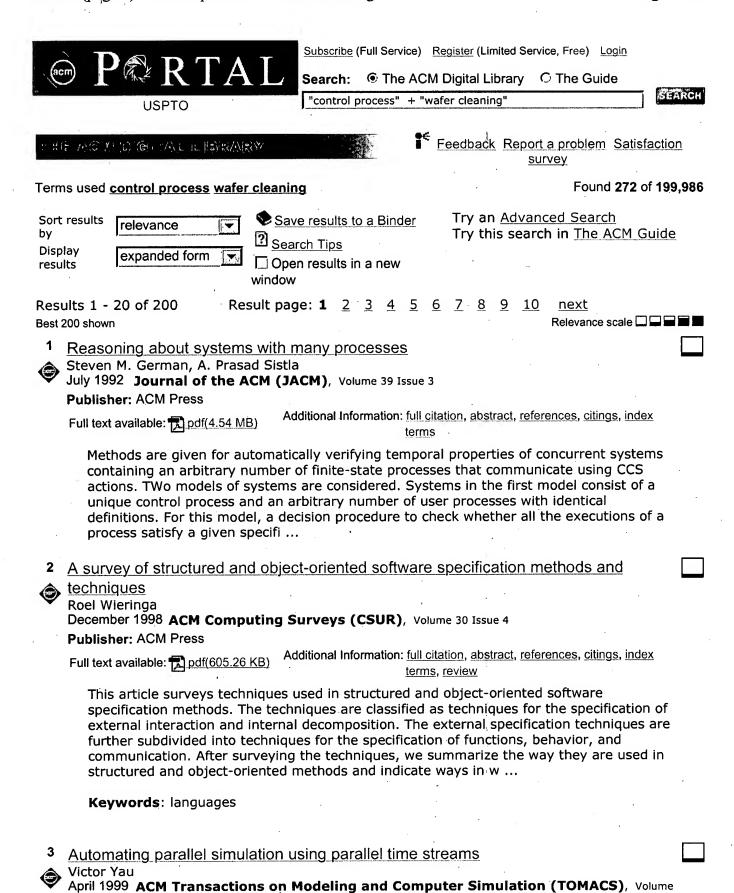
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9 Issue 2 Publisher: ACM Press This paper describes a package for parallel steady-state stochastic simulation that was designed to overcome problems caused by long simulation times experienced in our ongoing research in performance evaluation of high-speed and integrated-services communication networks, while maintaining basic statistical rigors of proper analysis of simulation output data. The package, named AKAROA, accepts ordinary (nonparallel) simulation programs, and alll further stages of stochastic simulation shou ...

Keywords: distributed simulation, interprocess communication, output analysis methodology, parallel processing, parallel simulation, parallel time streams, spectral analysis, speedup

4	Behavior modelling during software design William E. Riddle, Jack C. Wileden, John H. Sayler, Alan R. Segal, Allan M. Stavely May 1978 Proceedings of the 3rd international conference on Software engineering ICSE '78 Publisher: IEEE Press	
	Full text available: pdf(999.46 KB) Additional Information: full citation, abstract, references, citings, index terms	
	A modelling scheme is presented which provides a medium for the rigorous, formal and abstract specification of large-scale software system components. The scheme allows the description of component behavior without revealing or requiring the description of a component's internal operation. Both collections of sequential processes and the data objects which they share may be described. The scheme is of particular value during the early stages of software system design, when the system's modu	•
	Keywords : Desired behavior specification, Dream, Event-based models, Message transfer models, Non-procedural specification, Software design analysis, Software design languages, Software system behavior modelling	
5 ②	DREAM - an approach to designing large scale, concurrent software systems Jack C. Wileden January 1979 Proceedings of the 1979 annual conference ACM 79 Publisher: ACM Press	
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	The Design Realization, Evaluation And Modelling (DREAM) system is an automated support system for designers of large-scale, concurrent software systems. DREAM is intended to facilitate the orderly development of such software systems by supporting high-level, abstract design descriptions and the successive modification and elaboration of incomplete descriptions. DREAM also provides a basis for formulating arguments regarding the correctness of an evolving design at any stage during its dev	
6 ③	A Quantitative Evaluation of the Feasibility of, and Suitable Hardware Architectures for, an Adaptive, Parallel Finite-Element System Pamela Zave, George E. Cole September 1983 ACM Transactions on Mathematical Software (TOMS), Volume 9 Issue 3 Publisher: ACM Press Full text available: pdf(1.36 MB) Additional Information: full citation, references, citings, index terms	
7	A higrarchical controller for concurrent accessing of distributed databases	

③	August 1978 ACM SIGARCH Computer Architecture News, ACM SIGIR Forum, ACM SIGMOD Record, Volume 7, 13, 10 Issue 2, 2, 1	
	Publisher: ACM Press Full text available: pdf(460.93 KB) Additional Information: full citation, abstract, references	
	An access controller for a distributed database is a (central or distributed) structure which routes access requests to the different components of the database. Such a controller is also supposed to resolve the conflicts between concurrent requests, if any, such that deadlock situations never arise. In this paper, some architectures for distributed access controllers of distributed databases are investigated. In particular, three controllers with hierarchical architectures are considered. The co	
8 ③	H. Ronald Berlack January 1981 ACM SIGMETRICS Performance Evaluation Review, Proceedings of the 1981 ACM workshop/symposium on Measurement and evaluation of software quality, Volume 10 Issue 1	
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	The fundamental problems in the control of software are explored. The elements of control as they relate to communications is defined, and the implementation of these elements in solving the fundamental problems and achieving optimal control during a software development life cycle, is explained. Control is defined as a vehicle for communicating changes to established, agreed-upon baseline points, made up of documents and subsequent computer programs. By communicating change to t	
9	The role of artificial intelligence in fault-tolerant process-control systems F. B. Bastani, IR. Chen June 1988 Proceedings of the 1st international conference on Industrial and engineering applications of artificial intelligence and expert systems - Volume 2 IEA/AIE '88 Publisher: ACM Press	
10	Full text available: pdf(854.81 KB) Additional Information: full citation, references, citings, index terms Design of an Adaptive, Parallel Finite-Element System	
\$	Pamela Zave, Werner C. Rheinboldt March 1979 ACM Transactions on Mathematical Software (TOMS), Volume 5 Issue 1 Publisher: ACM Press Full text available: pdf(1.12 MB) Additional Information: full citation, references, citings, index terms	
11 �	An Approach to Program Behavior Modeling and Optimal Memory Control Percy Tzelnic, Izidor Gertner April 1982 Journal of the ACM (JACM), Volume 29 Issue 2 Publisher: ACM Press	
12	Full text available: pdf(1.37 MB) Additional Information: full citation, references, index terms A transputer-based parallel Lisp implementation	



M. D. Feng, C. K. Yuen

April 1992 Proceedings of the 1992 ACM annual conference on Communications CSC '92

Publisher: ACM Press

Full text available: pdf(816.59 KB) Additional Information: full citation, references, index terms

Keywords: parallel Lisp, speculative processing, transputer, tuple space

13 A hierarchical controller for concurrent accessing of distributed databases

Mohamed G. Gouda

August 1978 Proceedings of the fourth workshop on Computer architecture for nonnumeric processing CAW '78

Publisher: ACM Press

Full text available: pdf(401.90 KB)

Additional Information: full citation, abstract, references, citings, index terms

An access controller for a distributed database is a (central or distributed) structure which routes access requests to the different components of the database. Such a controller is also supposed to resolve the conflicts between concurrent requests, if any, such that deadlock situations never arise. In this paper, some architectures for distributed access controllers of distributed databases are investigated. In particular, three controllers with hierarchical architectures are c ...

14 XML access control: Access control of XML documents considering update



<u>operations</u>

Chung-Hwan Lim, Seog Park, Sang H. Son

October 2003 Proceedings of the 2003 ACM workshop on XML security XMLSEC '03

Publisher: ACM Press

Full text available: pdf(298.78 KB)

Additional Information: <u>full citation</u>, <u>abstract</u>, <u>references</u>, <u>citings</u>, <u>index</u>

As a large quantity of information is presented in XML format on the Web, there are increasing demands for XML security. Until now, research on XML security has been focused on the security of data communication using digital signatures or encryption technologies. As XML is also used for a data representation of data storage, XML security comes to involve not only communication security but also managerial security. Managerial security is guaranteed through access control, but existing XML acces ...

Keywords: XML document, XML update, access control

15 An approach to software configuration control

William Bryan, Stanley Siegel, Gary Whiteleather

January 1981 ACM SIGMETRICS Performance Evaluation Review , Proceedings of the 1981 ACM workshop/symposium on Measurement and evaluation of software quality, Volume 10 Issue 1

Publisher: ACM Press

Full text available: Rapdf(729.29 KB) Additional Information: full citation, abstract, index terms

The purpose of this paper is to discuss the process by which a system's life cycle and its associated life cycle products are managed to ensure the quality and integrity of the system. We call this process configuration control. Although many of the ideas in this paper are applicable to systems in general, the focus of this paper is on configuration control of systems with software content. It is becoming apparent to many, in both government and private ind ...

16 ②	Sven J. Fischer, Jan Achterberg, June 1993 Proceedings of the SIGCPR '93	s for managing information technology , Tsvi G. Vinig 1993 conference on Computer personnel research	
	Publisher: ACM Press	·	
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	these assumptions are made Technology (IT) is shaped in to carry out information syst how to plan for and control a	sed on a number of implicit and explicit assumptions. Usually, by the founder of a company. Management of Information much the same way. It is based on several assumptions how tems development, maintenance, information services, and all these activities. Based on such assumptions, the authors aches or paradigms to management	
17	Transformation of data flow a Bruno Alabiso	analysis models to object oriented design	
•	January 1988 ACM SIGPLAN No	otices, Conference proceedings on Object-oriented stems, languages and applications OOPSLA '88, Volume	
	Full text available: pdf(1.27 MB)	Additional Information: <u>full citation</u> , <u>abstract</u> , <u>references</u> , <u>citings</u> , <u>index</u> <u>terms</u>	
	Design. This transformation in Model, by enriching with Design Model. Semiformal transformation introduced to describe the O	egy to transform Data Flow Analysis into Object Oriented is performed by extracting information from the Data Flow sign decision and by finally producing an Object Oriented ransformation rules are described. Also a special notation is bject Oriented Design Model. The Model used to represent e originally proposed by Yourdon, comp	
18	Information systems security	design methods: implications for information systems	
\$	development Richard Baskerville	ng Surveys (CSUR), Volume 25 Issue 4	
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	increasing. It is important, the expertise in methods for spe found in three generations of framework for comparing an	systems is a serious issue because computer abuse is herefore, that systems analysts and designers develop ecifying information systems security. The characteristics of general information system design methods provide a dunderstanding current security design methods. These is that use checklists of controls, divide functional req	
	Keywords : checklists, contrand design, system modeling	rol, integrity, risk analysis, safety, structured systems analysis g	
19	Behavioral control for real-tin John P. Granieri, Welton Becket April 1995 Proceedings of the Publisher: ACM Press	t, Barry D. Reich, Jonathan Crabtree, Norman I. Badler 1995 symposium on Interactive 3D graphics SI3D '95	
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A system for controlling the behaviors of an interactive human-like agent, and executing them in real-time, is presented. It relies on an underlying model of continuous behavior as well as a discrete scheduling mechanism for changing behavior over time. A multiprocessing framework executes the behaviors and renders the motion of the agents in real-time. Finally we discuss the current state of our implementation and some areas of future work.

20 <u>Performance analysis of MSP: feature-rich high-speed transport protocol</u> Thomas F. La Porta, Mischa Schwartz

December 1993 IEEE/ACM Transactions on Networking (TON), Volume 1 Issue 6

Publisher: IEEE Press

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4	BRS	S343	6	(control same process) and (process same alarms same generation) and (alarms same thresholds) and wafer
5	BRS	S345	113	(control same process) and (process same alarms same generation) and (alarms same thresholds)
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11	BRS	S351	3012	S350 and wafer
12	BRS	S352	104	S350 and (wafers same baths)
13	BRS	S353	72	S350 and (wafers same baths same clean\$6)
14	BRS	S354	0	S350 and (wafers same baths same clean\$6) and (alarms same thresholds)
15	BRS	S355	5	S350 and (wafers same baths same clean\$6) and (alarms and thresholds)
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Sciences, 2004 - Taylor & Francis

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10	BRS	L10	300	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	(wafer same cleaning same liquid).clm.	2007/04/20 09:58

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11	BRS	L11		US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	(wafer same cleaning same liquid same alarm).clm.	2007/04/20 09:58
12	BRS	L12	0	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	(wafer same cleaning same liquid same threshold).clm.	2007/04/20 09:58
13	BRS	L13	474	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO DERWEN T; IBM_TDB	((wafer or semiconductor) same cleaning same liquid).clm.	2007/04/20 09:59
14	BRS	L14	0	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO DERWEN T; IBM_TDB	((wafer or semiconductor) same cleaning same liquid).clm. and (threshold same alarm	2007/04/20 09:59
15	BRS	L15	0	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO DERWEN T; IBM_TDB	((wafer or semiconductor) same cleaning same liquid).clm. and (threshold near alarm)	2007/04/20 10:00

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3	BRS	L3	17	US- PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWEN T; IBM_TDB	(wafer and cleaning and alarm).clm.	2007/04/20 09:46
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5	BRS	L5	2	US- PGPUB; USPAT; USOCR	("4375992" "4917123").PN.	2007/04/20 09:48

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Control system, control method, process system, and computer readable storage medium and computer ...

K Mori - 2006 - freepatentsonline.com

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A Guha, A Pavan, JCL Liu, BA Roberts - Multimedia, IEEE, 1995 - ieeexplore ieee.org ... the pro- duction of such advanced materials as **liquid** crys- tal ... a flaw that exceeds the preset **threshold**, the Flexbed system signals an **alarm** to the ...

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S Maeda, F Endo, H Makihira, H Kubota - Systems and Computers in Japan, 1998 - doi.wilev.com

... examined false alarms included in inspection results in actual **wafer** production and proposed a method to perform **threshold** setting based on the false **alarm** rate ... Related Articles - Web Search - BL Direct

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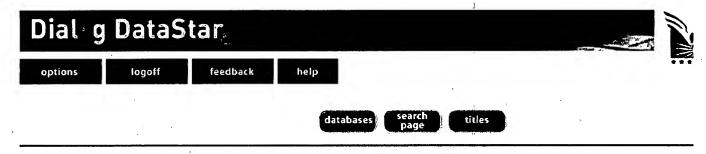
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Title

Artificial immunity based management system for a semiconductor production line.

Conference information

1997 IEEE International Conference on Systems, Man, and Cybernetics. Computational Cybernetics and Simulation, Orlando, FL, USA, 12-15 Oct. 1997.

Sponsor(s): Syst., Man, & Cybernetics Soc. IEEE.

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Publisher: IEEE, New York, NY, USA.

Author(s)

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Author affiliation

Mori, K., Tsukiyama, M., Ind. Electron. & Syst. Labs., Mitsubishi Electr. Corp., Hyogo, Japan.

A semiconductor production line is a large scale and complex system. It is considered to be difficult to control because there exist lots of malfunctions such as maintenance of equipment, equipment breakdown and imbalance of WIP to disturb production of wafers in the semiconductor production system. Methods and systems using simulations or expert systems have been used to solve these disturbances, the but semiconductor production environments change dynamically and therefore these methods alone do not yield a perfect control system. This paper presents a method applying an artificial immunity based system described by multi-agent nets, that adapts itself to a dynamical environment.

Descriptors

INTEGRATED-CIRCUIT-MANUFACTURE; LARGE-SCALE-SYSTEMS; PETRI-NETS;

PRODUCTION-CONTROL.

Classification codes

B0170E Production-facilities-and-engineering*;

B2570 Semiconductor-integrated-circuits;

B0250 Combinatorial-mathematics;

C1290F Systems-theory-applications-in-industry*;

C1340B Multivariable-control-systems;

C1160 Combinatorial-mathematics;

E0210E Combinatorial-mathematics*;

E1010 Production-management;

E1520 Manufacturing-processes;

E1540 Systems-theory-applications;

E1550 Control-technology-and-theory;

E3644A Semiconductor-industry.

Keywords

artificial-immunity-based-management-system; semiconductor-production-line; large-scale-complexsystem; malfunctions; maintenance; equipment-break-down; WIP-imbalance; wafer-production; expert-systems; multi-agent-nets; colored-Petri-nets; dynamical-environment.

Treatment codes

T Theoretical-or-mathematical.

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Conference-paper.

Availability

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